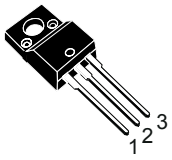
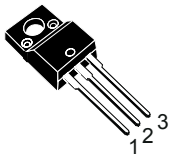
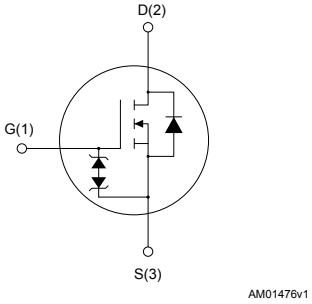
N-channel 800 V, 470 mΩ typ., 9 A MDmesh K5 Power MOSFET in a TO-220FP and TO-220FP ultra narrow leads packages



TO-220FP



TO-220FP
ultra narrow leads



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STF10N80K5	800 V	600 mΩ	9 A
STFU10N80K5			

- Ultra-low gate charge
- Very low FoM (figure of merit)
- Zener-protected
- 100% avalanche tested

Applications

- Switching applications

Description

These very high voltage N-channel Power MOSFETs are designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Product status links
STF10N80K5
STFU10N80K5

Product summary	
Order code	**STF10N80K5**
Marking	10N80K5
Package	TO-220FP
Packing	Tube
Order code	**STFU10N80K5**
Marking	10N80K5
Package	TO-220FP ultra narrow leads
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	800	V
V_{GS}	Gate-source voltage	±30	V
I_D	Drain current (continuous) at T_C = 25 °C	9	A
	Drain current (continuous) at T_C = 100 °C	6	
I_{DM}(1)	Drain current (pulsed)	36	A
P_{TOT}	Total power dissipation at T_C = 25 °C	30	W
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T_C = 25 °C)	2.5	kV
dv/dt(2)	Peak diode recovery voltage slope	4.5	V/ns
dv/dt(3)	MOSFET dv/dt ruggedness	50	V/ns
T_{stg}	Storage temperature range	-55 to 150	°C
T_J	Operating junction temperature range		°C

1. *Pulse width is limited by safe operating area.*
2. *I_{SD} ≤ 9 A, di/dt = 100 A/µs, V_{DS} (peak) < $V_{(BR)DSS}$, V_{DD} = 640 V.*
3. *V_{DD} ≤ 640 V.*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	4.2	°C/W
R_{thJA}	Thermal resistance, junction-to-ambient	62.5	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.)	3	A
E_{AS}	Single pulse avalanche energy (starting T_J = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	130	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified.

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	800	-	-	V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 800 V	-	-	1	µA
		V_{GS} = 0 V, V_{DS} = 800 V, T_C = 125 °C(1)	-	-	50	
I_{GSS}	Gate-body leakage current	V_{DS} = 0 V, V_{GS} = ±20 V	-	-	±10	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 100 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 4.5 A	-	470	600	mΩ

1. *Specified by design, not tested in production.*

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	635	-	pF
C_{oss}	Output capacitance		-	53	-	pF
C_{rss}	Reverse transfer capacitance		-	0.8	-	pF
$C_{o(tr)}$(1)	Equivalent output capacitance time related	V_{DS} = 0 to 640 V, V_{GS} = 0 V	-	85	-	pF
$C_{o(er)}$(2)	Equivalent output capacitance energy related		-	34	-	pF
R_g	Intrinsic gate resistance	f = 1 MHz, I_D = 0 A	-	6	-	Ω
Q_g	Total gate charge	V_{DD} = 640 V, I_D = 9 A, V_{GS} = 0 to 10 V (see the Figure 15. Test circuit for gate charge behavior)	-	22	-	nC
Q_{gs}	Gate-source charge		-	5.5	-	nC
Q_{gd}	Gate-drain charge		-	13.2	-	nC

1. *$C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*
2. *$C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 400 V, I_D = 4.5 A, R_G = 4.7 Ω, V_{GS} = 10 V (see the Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform)	-	14.5	-	ns
t_r	Rise time		-	11	-	ns
$t_{d(off)}$	Turn-off delay time		-	35	-	ns
t_f	Fall time		-	14	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-	-	9	A
I_{SDM}(1)	Source-drain current (pulsed)		-	-	36	A
V_{SD}(2)	Forward on voltage	V_{GS} = 0 V, I_{SD} = 9 A	-	-	1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 9 A, di/dt = 100 A/µs, V_{DD} = 60 V (see the Figure 16. Test circuit for inductive load switching and diode recovery times)	-	370	-	ns
Q_{rr}	Reverse recovery charge		-	4.58	-	µC
I_{RRM}	Reverse recovery current		-	25	-	A
t_{rr}	Reverse recovery time	I_{SD} = 9 A, di/dt = 100 A/µs, V_{DD} = 60 V, T_J = 150 °C (see the Figure 16. Test circuit for inductive load switching and diode recovery times)	-	520	-	ns
Q_{rr}	Reverse recovery charge		-	5.88	-	µC
I_{RRM}	Reverse recovery current		-	22.5	-	A

1. *Pulse width is limited by safe operating area.*
2. *Pulse test: pulse duration = 300 µs, duty cycle 1.5%.*

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

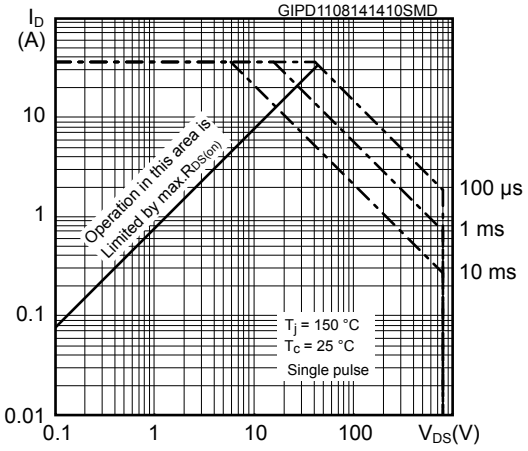


Figure 2. Normalized transient thermal impedance

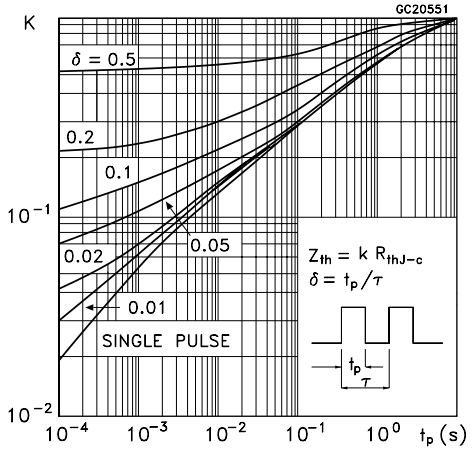


Figure 3. Typical output characteristics

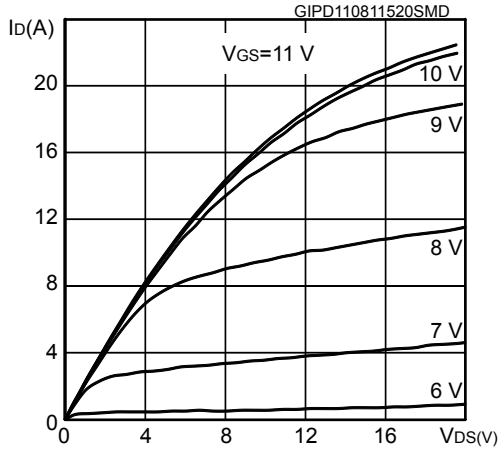


Figure 4. Typical transfer characteristics

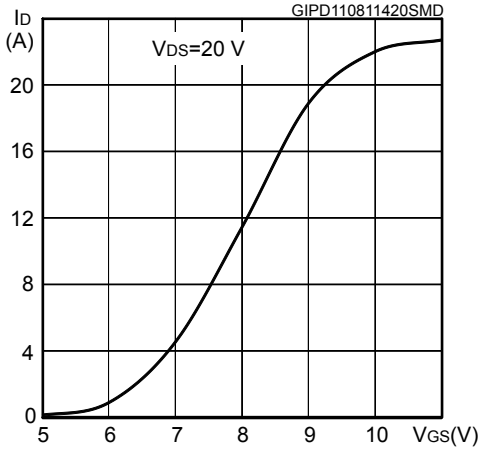


Figure 5. Typical gate charge characteristics

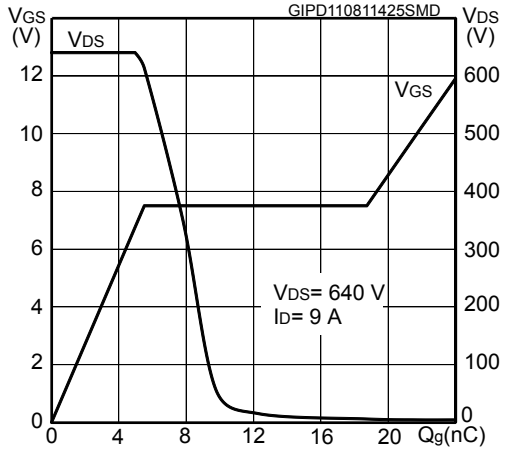


Figure 6. Typical drain-source on-resistance

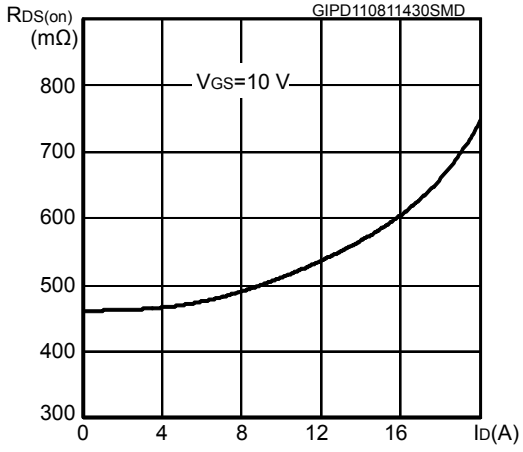


Figure 7. Typical capacitance characteristics

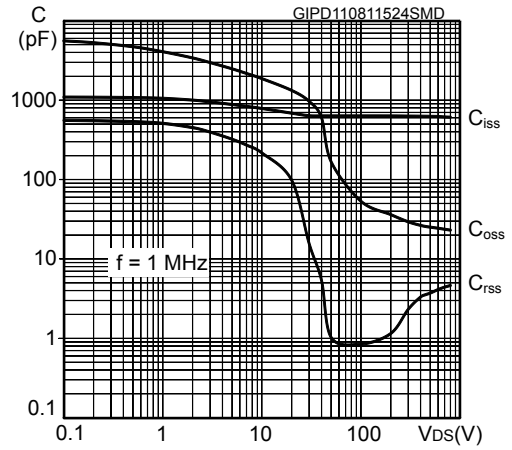


Figure 8. Typical output capacitance stored energy

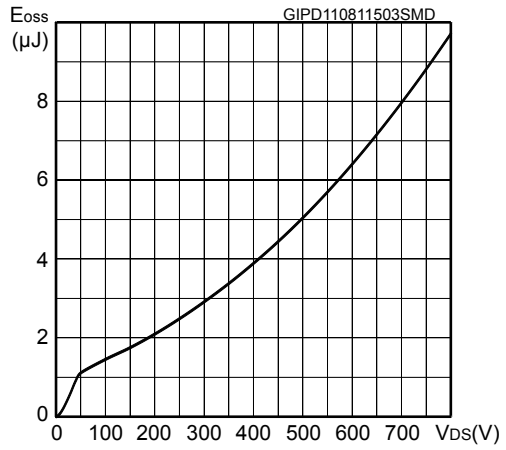


Figure 9. Normalized gate threshold vs temperature

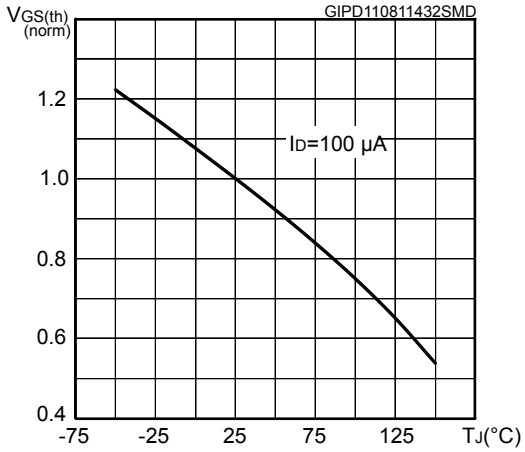


Figure 10. Normalized on-resistance vs temperature

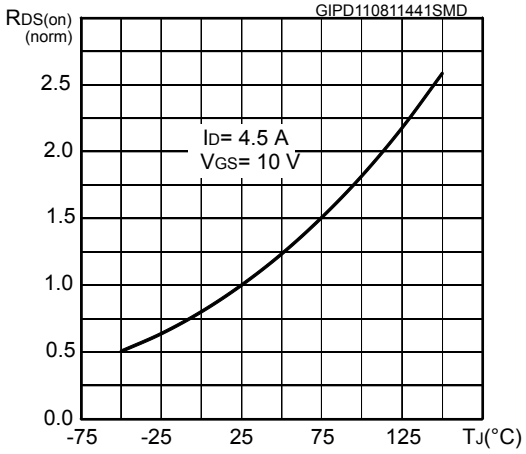


Figure 11. Normalized breakdown voltage vs temperature

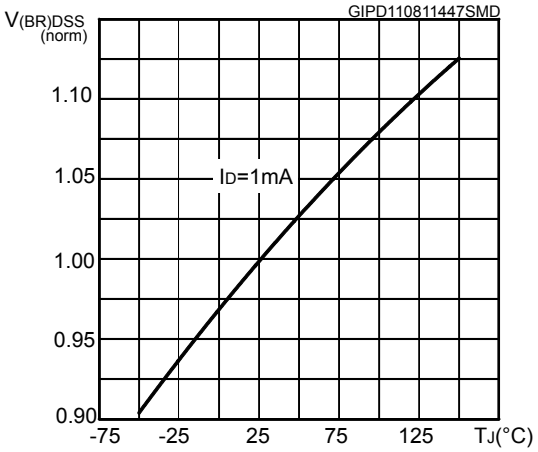


Figure 12. Typical reverse diode forward characteristics

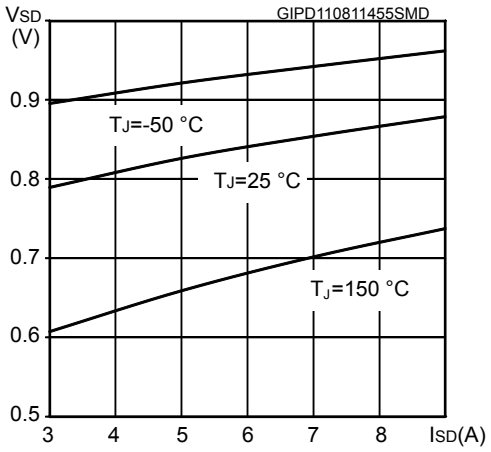
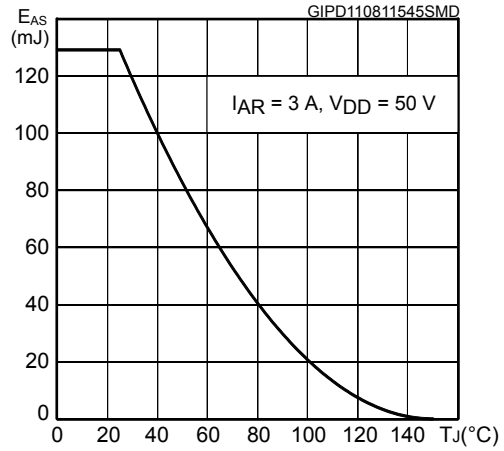
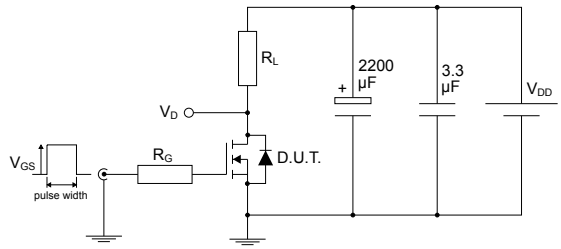


Figure 13. **Maximum avalanche energy vs temperature**



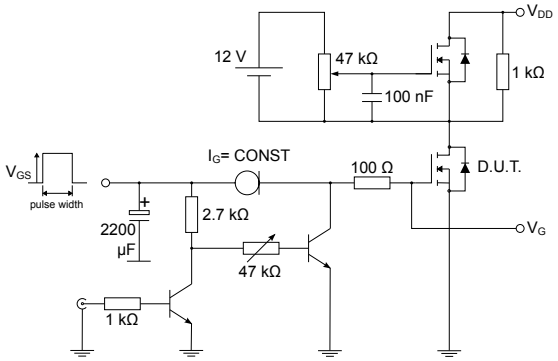
3 Test circuits

Figure 14. Test circuit for resistive load switching times



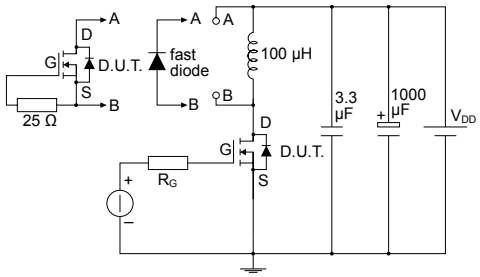
AM01468v1

Figure 15. Test circuit for gate charge behavior



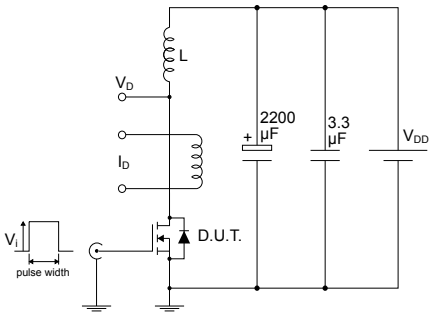
AM01469v1

Figure 16. Test circuit for inductive load switching and diode recovery times



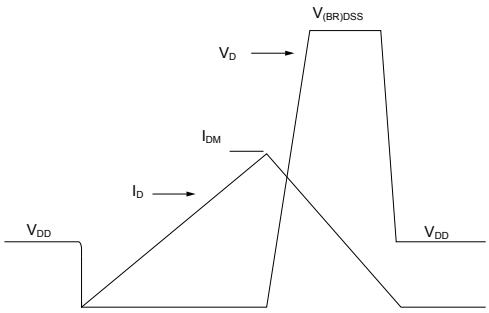
AM01470v1

Figure 17. Unclamped inductive load test circuit



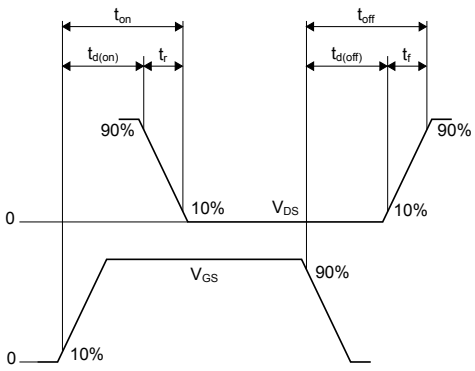
AM01471v1

Figure 18. Unclamped inductive waveform



AM01472v1

Figure 19. Switching time waveform



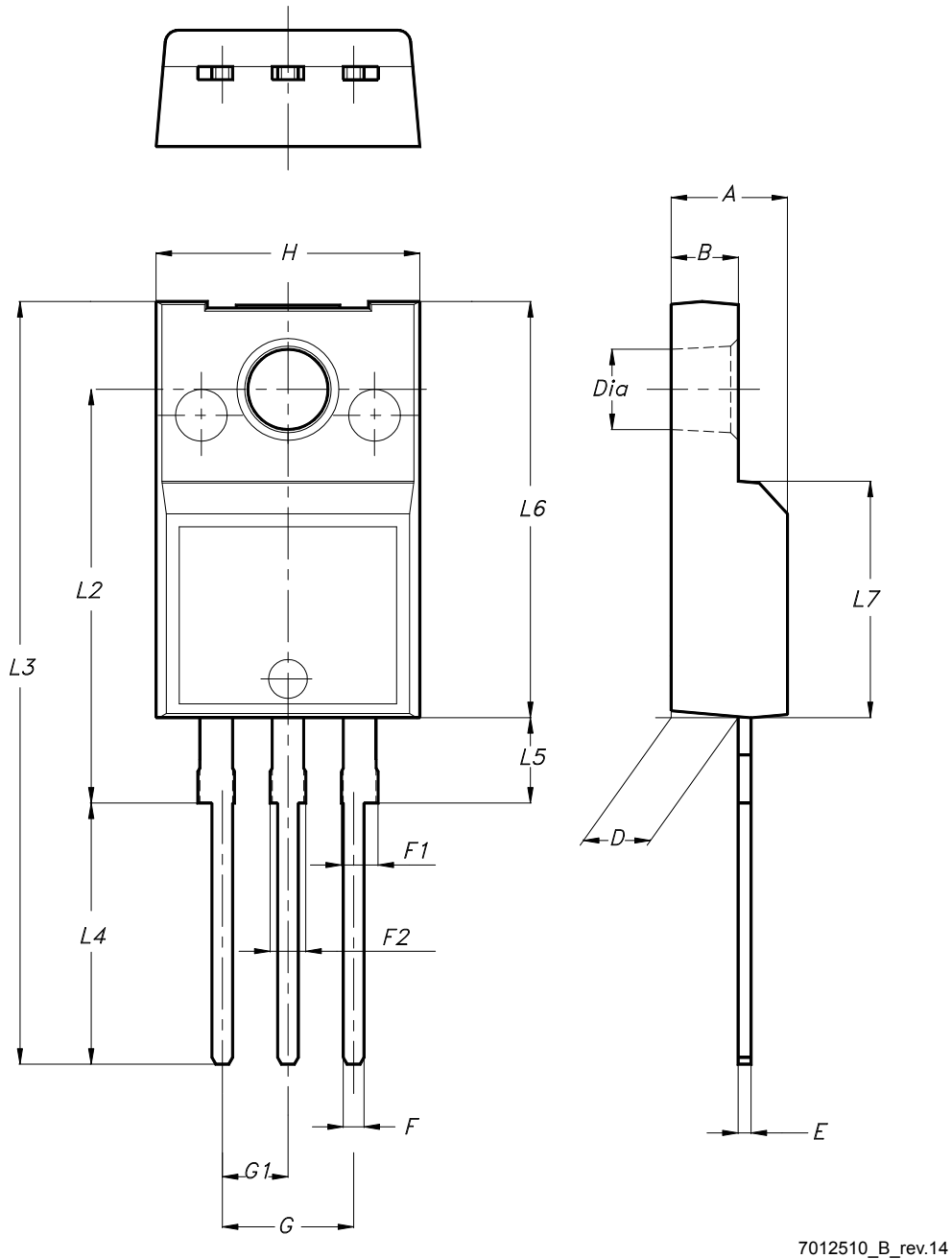
AM01473v1

4 Package information

To meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-220FP type B package information

Figure 20. TO-220FP type B package outline



7012510_B_rev.14

Table 8. **TO-220FP type B package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
E	0.45		0.70
F	0.75		1.00
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.20
G1	2.40		2.70
H	10.00		10.40
L2		16.00	
L3	28.60		30.60
L4	9.80		10.60
L5	2.90		3.60
L6	15.90		16.40
L7	9.00		9.30
Dia	3.00		3.20

4.2 TO-220FP ultra narrow leads package information

Figure 21. **TO-220FP ultra narrow leads package outline**

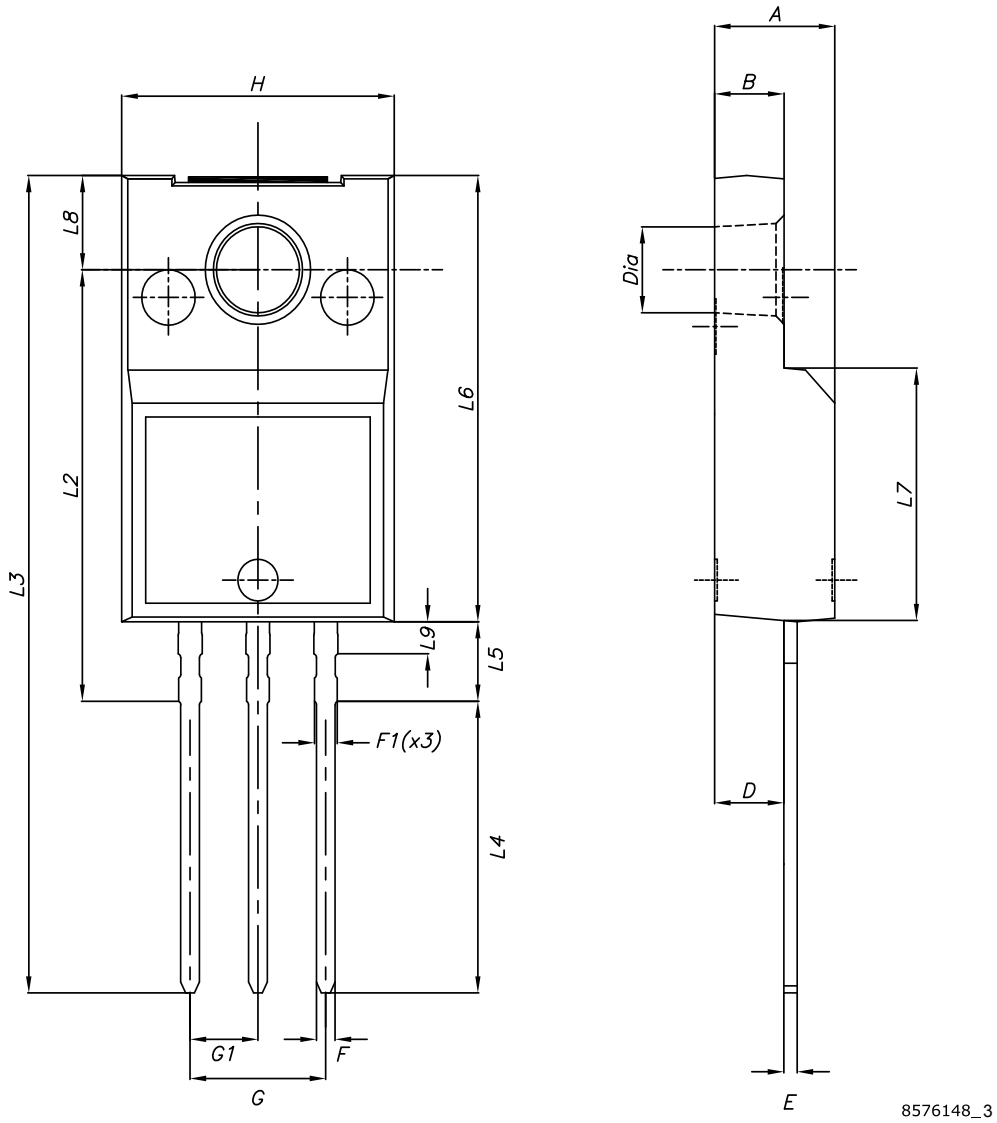


Table 9. **TO-220FP ultra narrow leads mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
E	0.45		0.60
F	0.65		0.75
F1	-		0.90
G	4.95		5.20
G1	2.40	2.54	2.70
H	10.00		10.40
L2	15.10		15.90
L3	28.50		30.50
L4	10.20		11.00
L5	2.50		3.10
L6	15.60		16.40
L7	9.00		9.30
L8	3.20		3.60
L9	-		1.30
Dia.	3.00		3.20

Revision history

Table 10. **Document revision history**

Date	Revision	Changes
23-Jun-2014	1	First release.
13-Aug-2014	2	Document status promoted from preliminary to production data. Inserted *Section 3: Electrical characteristics (curves)*. Minor text changes.
17-Sep-2014	3	Updated title, features and description in cover page.
05-Nov-2014	4	Updated Section 3: Electrical characteristics (curves). Minor text changes.
08-Sep-2016	5	Added the order code STFU10N80K5 and the relative *Section 4.2: "TO-220FP ultra narrow leads package information"*.
03-Apr-2026	6	Updated Section 4: Package information. Minor text changes.

Contents

1 **Electrical ratings** 2
2 **Electrical characteristics** 3
2.1 Electrical characteristics (curves) 5
3 **Test circuits** 8
4 **Package information** 9
4.1 TO-220FP type B package information 9
4.2 TO-220FP ultra narrow leads package information 11
Revision history 13

IMPORTANT NOTICE – READ CAREFULLY

STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice.

In the event of any conflict between the provisions of this document and the provisions of any contractual arrangement in force between the purchasers and ST, the provisions of such contractual arrangement shall prevail.

The purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgment.

The purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of the purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

If the purchasers identify an ST product that meets their functional and performance requirements but that is not designated for the purchasers' market segment, the purchasers shall contact ST for more information.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2026 STMicroelectronics – All rights reserved